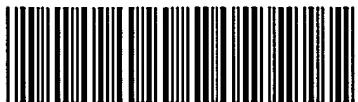


**Search Notes****Application/Control No.**

09/650,218

**Examiner**

Shin-Hon Chen

**Applicant(s)/Patent under Reexamination**

AVERY ET AL.

**Art Unit**

2131

**SEARCHED**

Class	Subclass	Date	Examiner
713	200, 201	7/28/2005	S.C.
709	219, 217	7/28/2005	S.C.
709	230, 328	7/28/2005	S.C.
382	124, 188	8/1/2005	S.C.
340	825.31	8/1/2005	S.C.
340	825.34, 5	8/2/2005	S.C.
340	5.5	8/2/2005	S.C.
49	68	8/3/2005	S.C.
382	115	8/3/2005	S.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
709	219,217	7/28/2005	S.C.
382	115, 124	8/1/2005	S.C.
340	825.31	8/1/2005	S.C.
340/825.34, 5.5, 5.81-5.86; 49/68		8/3/2005	S.C.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/28/2005	S.C.
NPL, EIC Search	8/1/2005	S.C.
Consulted with examiner Chris Revak, Ho Song	8/2/2005	S.C.
Consult with Tech Center 2635 primary examiner Edwin Holloway	8/3/2005	S.C.